

Philips Semiconductors

Product specification

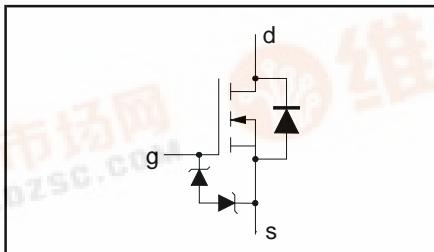
TrenchMOS™ transistor Logic level FET

PHT6N03LT

FEATURES

- 'Trench' technology
- Very low on-state resistance
- Fast switching
- Stable off-state characteristics
- High thermal cycling performance
- Surface mounting package

SYMBOL



QUICK REFERENCE DATA

$V_{DSS} = 30 \text{ V}$
$I_D = 5.9 \text{ A}$
$R_{DS(ON)} \leq 30 \text{ m}\Omega (V_{GS} = 5 \text{ V})$
$R_{DS(ON)} \leq 28 \text{ m}\Omega (V_{GS} = 10 \text{ V})$

GENERAL DESCRIPTION

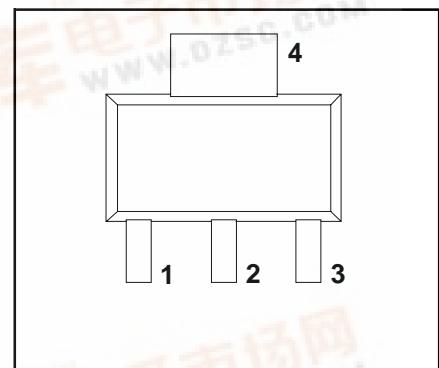
N-channel enhancement mode logic level field-effect power transistor using 'trench' technology. The device has very low on-state resistance. It is intended for use in dc to dc converters and general purpose switching applications.

The PHT6N03LT is supplied in the SOT223 surface mounting package.

PINNING

PIN	DESCRIPTION
1	gate
2	drain
3	source
tab	drain

SOT223



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DSS}	Drain-source voltage	$T_j = 25 \text{ }^\circ\text{C to } 150 \text{ }^\circ\text{C}$	-	30	V
V_{DGR}	Drain-gate voltage	$T_j = 25 \text{ }^\circ\text{C to } 150 \text{ }^\circ\text{C}; R_{GS} = 20 \text{ k}\Omega$	-	30	V
V_{GS}	Gate-source voltage		-	± 13	V
I_D	Continuous drain current	$T_{amb} = 25 \text{ }^\circ\text{C}; V_{GS} = 10 \text{ V}$	-	5.9	A
I_{DM}	Pulsed drain current	$T_{amb} = 100 \text{ }^\circ\text{C}; V_{GS} = 10 \text{ V}$	-	4.1	A
P_D	Total power dissipation		-	23.6	A
T_j, T_{stg}	Operating junction and storage temperature	$T_{amb} = 25 \text{ }^\circ\text{C}$	- 55	1.8	W
				150	$^\circ\text{C}$

ESD LIMITING VALUE

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_C	Electrostatic discharge capacitor voltage, all pins	Human body model (100 pF, 1.5 k Ω)	-	2	kV

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th j-sp}$	Thermal resistance junction to solder point	mounted on any pcb	-	-	15	K/W
$R_{th j-a}$	Thermal resistance junction to ambient	mounted on test pcb of fig:17	-	70	-	K/W

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ELECTRICAL CHARACTERISTICS $T_j = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	30	-	-	V
$V_{(\text{BR})\text{GSS}}$	Gate-source breakdown voltage	$I_G = 1 \text{ mA}$	27	-	-	V
$V_{GS(\text{TO})}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	10	-	-	V
$R_{DS(\text{ON})}$	Drain-source on-state resistance	$V_{GS} = 5 \text{ V}; I_D = 3.2 \text{ A}$ $V_{GS} = 10 \text{ V}; I_D = 3.2 \text{ A}$ $V_{GS} = 5 \text{ V}; I_D = 3.2 \text{ A}; T_j = 150^\circ\text{C}$ $V_{DS} = 25 \text{ V}; I_D = 5.9 \text{ A}$ $V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}$	1 0.6 $T_j = 150^\circ\text{C}$ $T_j = -55^\circ\text{C}$ $T_j = 150^\circ\text{C}$	1.5 - - 24 18	2 - - 30 28	V mΩ mΩ mΩ
g_{fs}	Forward transconductance	$V_{GS} = 5 \text{ V}; I_D = 3.2 \text{ A}$	-	-	51	mΩ
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 10 \text{ V}; I_D = 3.2 \text{ A}$	-	14	-	S
I_{GSS}	Gate source leakage current	$V_{DS} = 25 \text{ V}; I_D = 5.9 \text{ A}$ $V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}$ $V_{GS} = \pm 5 \text{ V}; V_{DS} = 0 \text{ V}$	8 $T_j = 150^\circ\text{C}$ $T_j = 150^\circ\text{C}$	0.05 - 0.02	10 500 1	μA μA μA
$Q_{g(\text{tot})}$	Total gate charge	$I_D = 5.9 \text{ A}; V_{DD} = 24 \text{ V}; V_{GS} = 5 \text{ V}$	-	24	-	nC
Q_{gs}	Gate-source charge		-	3	-	nC
Q_{gd}	Gate-drain (Miller) charge		-	11	-	nC
$t_{d\text{ on}}$	Turn-on delay time	$V_{DD} = 15 \text{ V}; I_D = 5.9 \text{ A}$	-	30	45	ns
t_r	Turn-on rise time	$V_{GS} = 5 \text{ V}; R_G = 5 \Omega$	-	80	130	ns
$t_{d\text{ off}}$	Turn-off delay time	Resistive load	-	95	135	ns
t_f	Turn-off fall time		-	40	55	ns
L_d	Internal drain inductance	Measured from tab to centre of die	-	3.5	-	nH
L_d	Internal drain inductance	Measured from drain lead to centre of die	-	3.5	-	nH
L_s	Internal source inductance	Measured from source lead to source bond pad	-	7.5	-	nH
C_{iss}	Input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	1050	-	pF
C_{oss}	Output capacitance		-	270	-	pF
C_{rss}	Feedback capacitance		-	140	-	pF

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS $T_j = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_s	Continuous source current (body diode)		-	-	5.9	A
I_{sM}	Pulsed source current (body diode)		-	-	10	A
V_{SD}	Diode forward voltage	$I_F = 5.9 \text{ A}; V_{GS} = 0 \text{ V}$	-	0.75	1.2	V
t_{rr}	Reverse recovery time	$I_F = 5.9 \text{ A}; -dI_F/dt = 100 \text{ A}/\mu\text{s}$	-	100	-	ns
Q_{rr}	Reverse recovery charge	$V_{GS} = -10 \text{ V}; V_R = 25 \text{ V}$	-	0.4	-	μC

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AVALANCHE LIMITING VALUE

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
W_{DSS}	Drain-source non-repetitive unclamped inductive turn-off energy	$I_D = 5.9 \text{ A}$; $V_{DD} \leq 15 \text{ V}$; $V_{GS} = 10 \text{ V}$; $R_{GS} = 50 \Omega$; $T_{amb} = 25^\circ\text{C}$	-	60	mJ

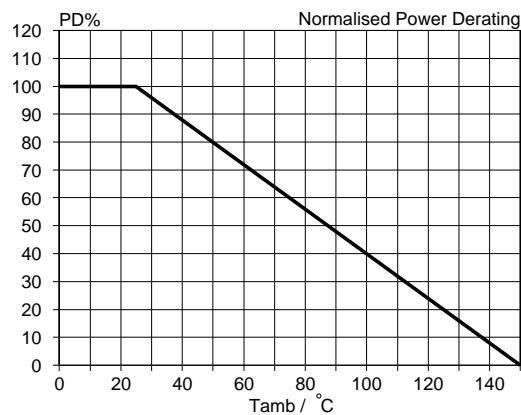


Fig. 1. Normalised power dissipation.
 $PD\% = 100 \cdot P_D / P_{D, 25^\circ\text{C}} = f(T_{amb})$

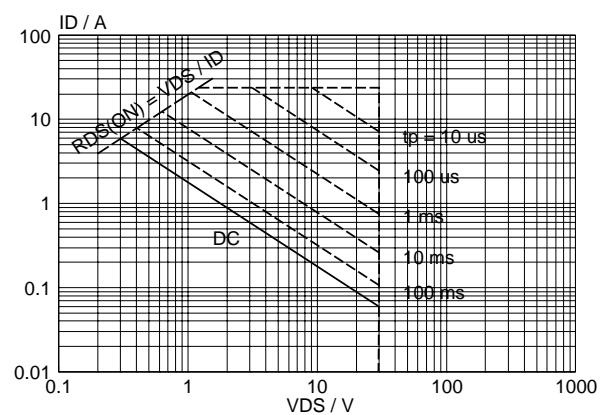


Fig. 3. Safe operating area. $T_{amb} = 25^\circ\text{C}$
 I_D & $I_{DM} = f(V_{DS})$; I_{DM} single pulse; parameter t_p

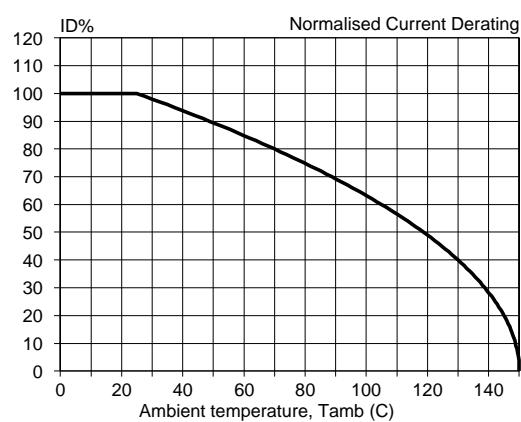


Fig. 2. Normalised continuous drain current.
 $ID\% = 100 \cdot I_D / I_{D, 25^\circ\text{C}} = f(T_{amb})$; conditions: $V_{GS} \geq 5 \text{ V}$

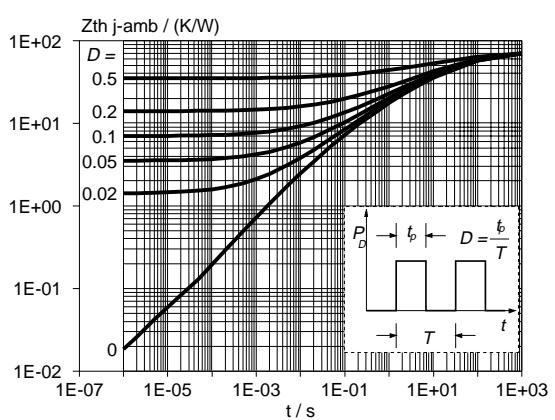


Fig. 4. Transient thermal impedance.
 $Z_{th,j-amb} = f(t)$; parameter $D = t_p/T$

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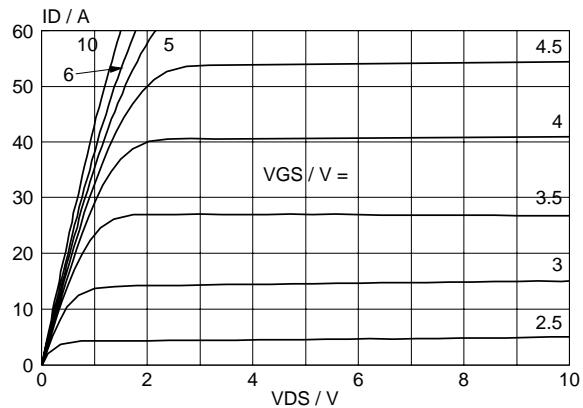


Fig.5. Typical output characteristics, $T_j = 25^\circ\text{C}$.
 $I_D = f(V_{DS})$; parameter V_{GS}

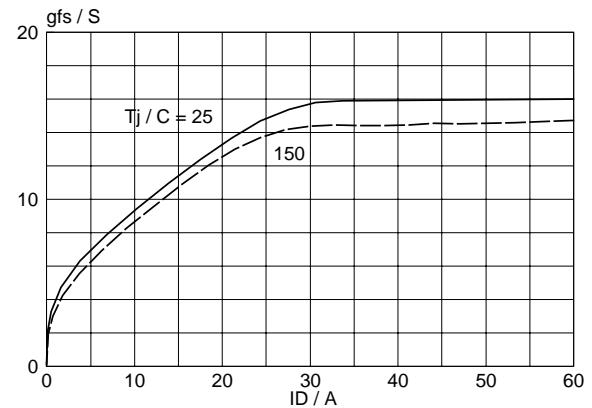


Fig.8. Typical transconductance, $T_j = 25^\circ\text{C}$.
 $g_{fs} = f(I_D)$; conditions: $V_{DS} = 25\text{ V}$

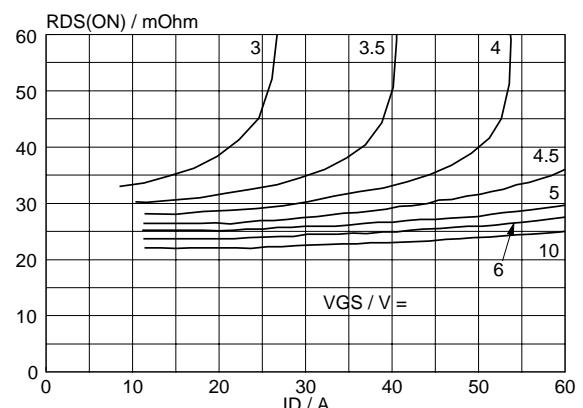


Fig.6. Typical on-state resistance, $T_j = 25^\circ\text{C}$.
 $R_{DS(ON)} = f(I_D)$; parameter V_{GS}

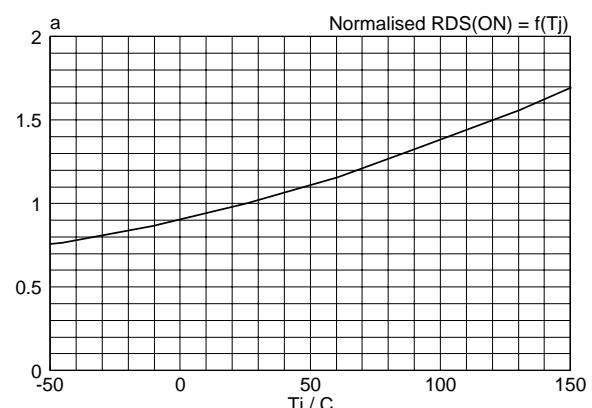


Fig.9. Normalised drain-source on-state resistance.
 $a = R_{DS(ON)}/R_{DS(ON)25^\circ\text{C}} = f(T_j)$; $I_D = 3.2\text{ A}$; $V_{GS} = 5\text{ V}$

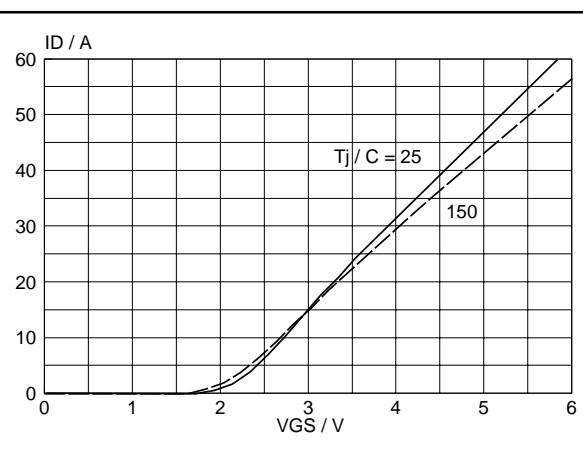


Fig.7. Typical transfer characteristics.
 $I_D = f(V_{GS})$; conditions: $V_{DS} = 25\text{ V}$; parameter T_j

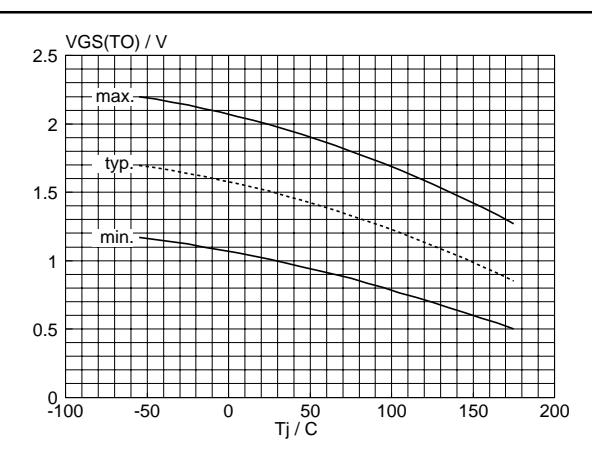


Fig.10. Gate threshold voltage.
 $V_{GS(TO)} = f(T_j)$; conditions: $I_D = 1\text{ mA}$; $V_{DS} = V_{GS}$

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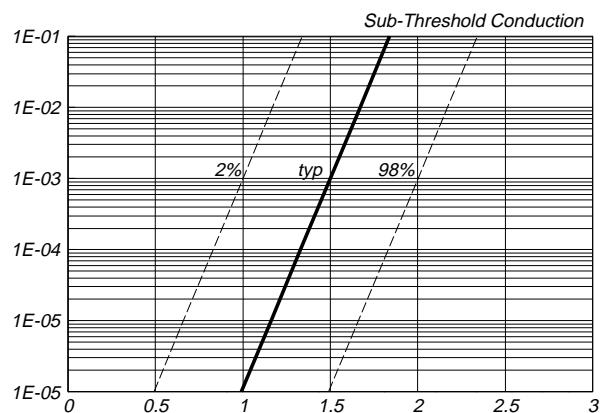


Fig.11. Sub-threshold drain current.
 $I_D = f(V_{GS})$; conditions: $T_j = 25^\circ\text{C}$; $V_{DS} = V_{GS}$

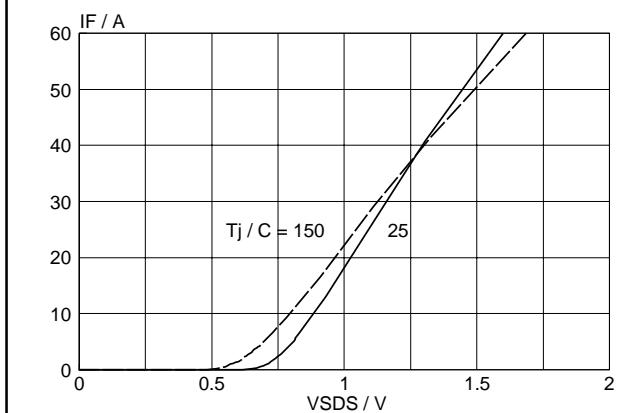


Fig.14. Typical reverse diode current.
 $I_F = f(V_{SDS})$; conditions: $V_{GS} = 0\text{ V}$; parameter T_j

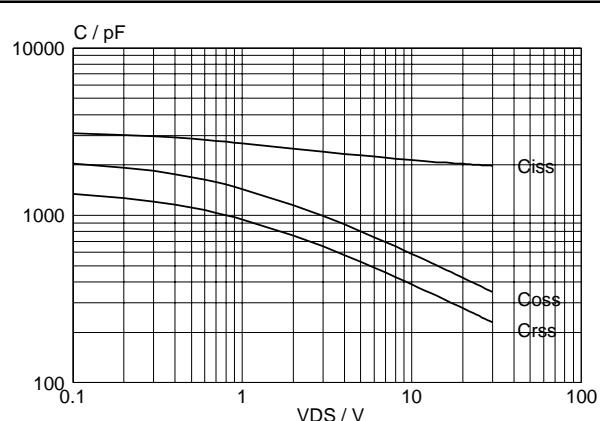


Fig.12. Typical capacitances, C_{iss} , C_{oss} , C_{rss} .
 $C = f(V_{DS})$; conditions: $V_{GS} = 0\text{ V}$; $f = 1\text{ MHz}$

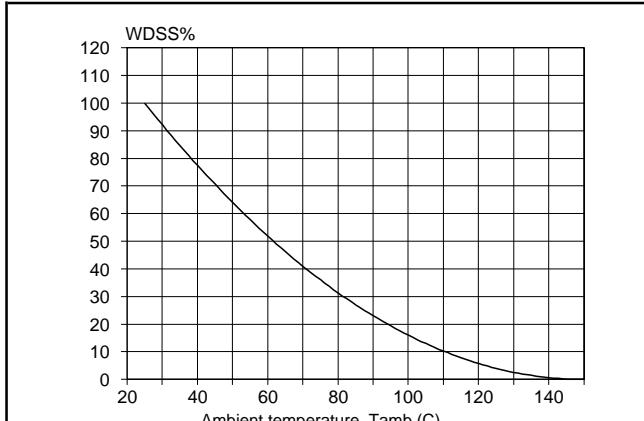


Fig.15. Normalised avalanche energy rating.
 $W_{DSS}\% = f(T_{amb})$; conditions: $I_D = 5.9\text{ A}$

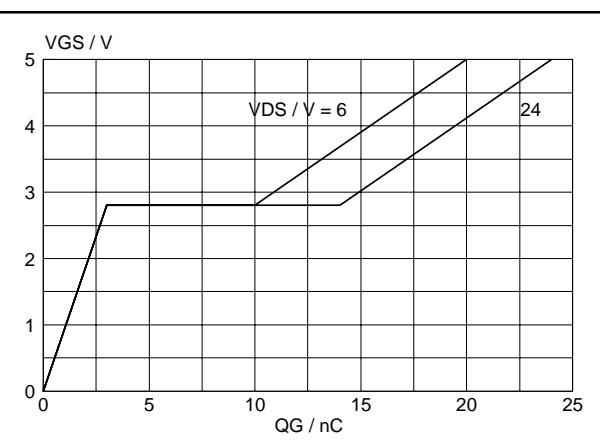


Fig.13. Typical turn-on gate-charge characteristics.
 $V_{GS} = f(Q_G)$; conditions: $I_D = 5.9\text{ A}$; parameter V_{DS}

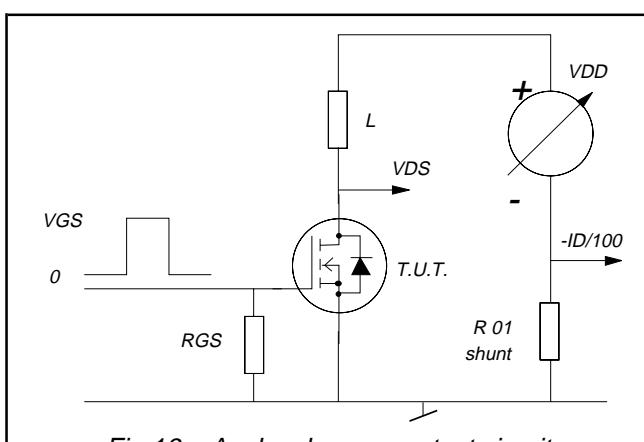
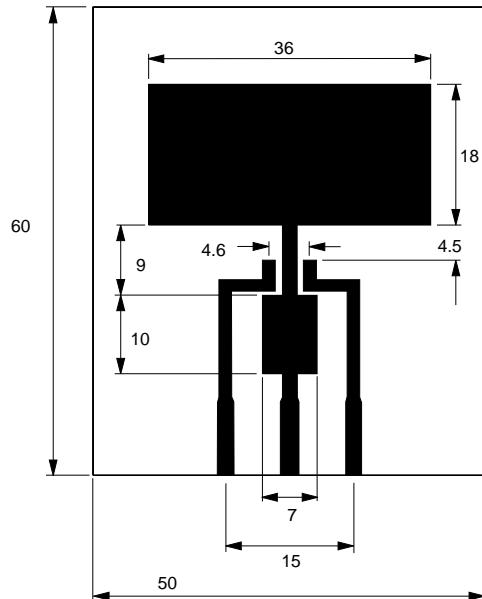


Fig.16. Avalanche energy test circuit.
 $W_{DSS} = 0.5 \cdot L I_D^2 \cdot BV_{DSS} / (BV_{DSS} - V_{DD})$

**TrenchMOS™ transistor
Logic level FET****PHT6N03LT****PRINTED CIRCUIT BOARD***Dimensions in mm.*

*Fig. 17. PCB for thermal resistance and power rating for SOT223.
PCB: FR4 epoxy glass (1.6 mm thick), copper laminate (35 µm thick).*